

### **MOSFET**

### StrongIRFET™2 Power-Transistor, 30 V

### **Features**

- Optimized for a wide range of applications
- N-channel, logic level
- 100% avalanche tested
- 175°C rated
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

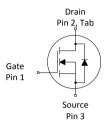
### **Product validation**

Qualified according to JEDEC Standard

Table 1 Key Performance Parameters

Parameter	Value	Unit						
$V_{ m DS}$	30	V						
$R_{\mathrm{DS(on),max}}$	1.05	mΩ						
I <sub>D</sub>	210	A						
$Q_{ m oss}$	176	nC						
Q <sub>g</sub> (0V4.5V)	108	nC						









Type/Ordering Code	Package	Marking	Related Links
IPP011N03LF2S	PG-TO220-3	011N03F2	-

### Public

# StrongIRFET™2 Power-Transistor, 30 V IPP011N03LF2S



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## 1 Maximum ratings

unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
raiametei	Syllibot	Min.	Тур.	Max.	Offic	Note/ Test Condition
Continuous drain current <sup>1)</sup>	$I_{D}$	-	-	210 163 46	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =40 °C/W <sup>2)</sup>
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	840	А	<i>T</i> <sub>C</sub> =25 °C
Avalanche energy, single pulse <sup>4)</sup>	E <sub>AS</sub>	-	-	2514 5028	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$ $I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 $\Omega$
Gate source voltage	$V_{GS}$	-20	-	20	V	-
Power dissipation	$P_{tot}$	-	-	375 3.8	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =40 °C/W <sup>2)</sup>
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-55	-	175	°C	-

<sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.

<sup>3)</sup> See Diagram 3 for more detailed information

<sup>4)</sup> See Diagram 13 for more detailed information



## 2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Symbol	Min.	Тур.	Мах.	Oilit	Note/ Test Condition
Thermal resistance, junction - case	$R_{thJC}$	-	-	0.4	°C/W	-
Thermal resistance, junction - ambient, cm² cooling area <sup>5)</sup>	$R_{thJA}$	-	-	40	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	$R_{thJA}$	-	-	62	°C/W	-

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



## 3 Electrical characteristics

unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Syllibot	Min.	Тур.	Мах.		Note/ Test Condition
Drain-source breakdown voltage	$V_{(BR)DSS}$	30	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =10 mA
Gate threshold voltage	$V_{\rm GS(th)}$	1.35	1.85	2.35	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \mu{\rm A}$
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μΑ	$V_{\rm DS}$ =30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C
Gate-source leakage current	$I_{GSS}$	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V
Drain-source on-state resistance <sup>6)</sup>	$R_{\rm DS(on)}$	-	0.91 1.0	1.05 1.5	mΩ	$V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =50 A
Gate resistance	$R_{G}$	-	1.8	-	Ω	-
Transconductance <sup>7)</sup>	$g_{fs}$	200	-	-	S	$ V_{\rm DS}  \ge 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 100 \text{ A}$

<sup>&</sup>lt;sup>6)</sup> R<sub>DS(on)</sub> is specified at a distance of 1.8 mm distance to the package body; mounting at a larger distance increases the overall package resistance of approximately 0.04 mOhm/mm per leg.

Table 5 Dynamic characteristics

Doromotor	Cymphol		Values			Note / Test Condition
Parameter	Symbol	Min.	Min. Typ. Max.		Unit	Note/ Test Condition
Input capacitance	C <sub>iss</sub>	-	15100	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =15 V, <i>f</i> =1 MHz
Output capacitance	C <sub>oss</sub>	-	2910	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =15 V, <i>f</i> =1 MHz
Reverse transfer capacitance	C <sub>rss</sub>	-	720	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =15 V, <i>f</i> =1 MHz
Turn-on delay time	$t_{ m d(on)}$	-	46	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	105	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	60	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	$t_{ m f}$	-	33	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Table 6 Gate charge characteristics 8)

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailietei	Syllibot	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	47	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	28	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V
Gate to drain charge	$Q_{\mathrm{gd}}$	-	31	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V

<sup>7)</sup> Defined by design. Not subject to production test.



Table 6 Gate charge characteristics 8)

Dorometer	Symbol	Values			Unit	Note/Test Condition
Parameter	Symbol	Min.	Тур.	Мах.		Note/ Test Condition
Switching charge	$Q_{sw}$	-	49	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total <sup>9)</sup>	$Q_{\mathrm{g}}$	-	108	162	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V
Gate plateau voltage	$V_{ m plateau}$	-	3.1	-	V	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total <sup>9)</sup>	$Q_{\mathrm{g}}$	-	224	336	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total, sync. FET <sup>9)</sup>	$Q_{g(sync)}$	-	95	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 4.5 V
Output charge <sup>9)</sup>	$Q_{\rm oss}$	-	176	-	nC	$V_{\rm DS}$ =15 V, $V_{\rm GS}$ =0 V

<sup>8)</sup> See "Gate charge waveforms" for parameter definition

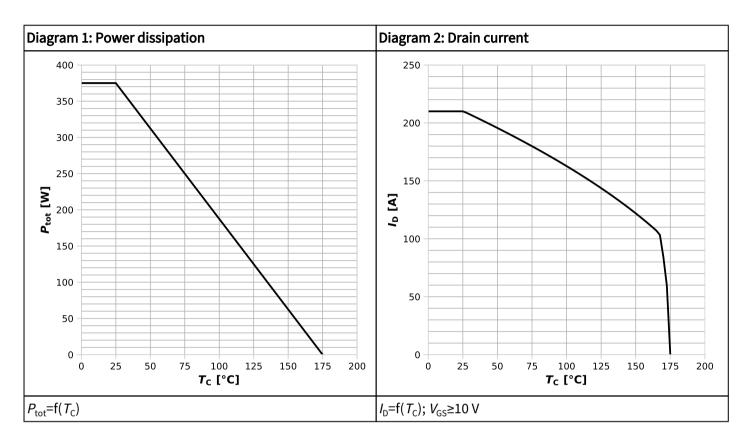
### Table 7 Reverse diode

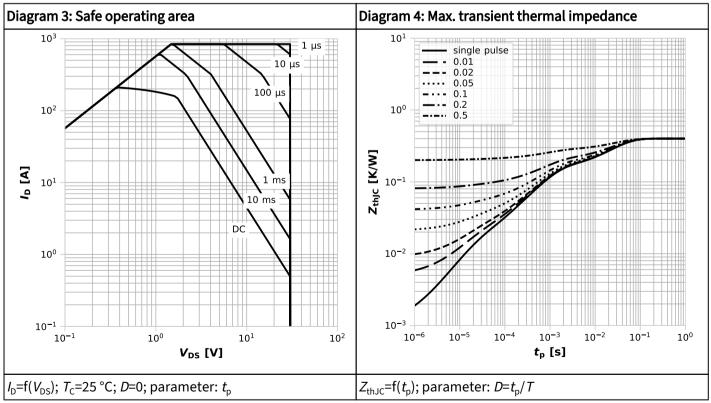
Parameter	Symbol	Values			Unit	Note / Took Condition
rarameter	Symbol	Min.	Тур.	Мах.	Ollic	Note/ Test Condition
Diode continuous forward current	I <sub>s</sub>	-	-	173	А	<i>T</i> <sub>C</sub> =25 °C
Diode pulse current	I <sub>S,pulse</sub>	-	-	840	А	<i>T</i> <sub>c</sub> =25 °C
Diode forward voltage	$V_{\rm SD}$	-	0.82	1.0	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =100 A, $T_{\rm j}$ =25 °C
Reverse recovery time	t <sub>rr</sub>	-	36	-	ns	$V_{\rm R}$ =15 V, $I_{\rm F}$ =100 A, d $i_{\rm F}$ /d $t$ =500 A/ $\mu$ s
Reverse recovery charge	$Q_{\rm rr}$	-	160	-	nC	$V_{\rm R}$ =15 V, $I_{\rm F}$ =100 A, d $i_{\rm F}$ /d $t$ =500 A/ $\mu$ s

<sup>9)</sup> Defined by design. Not subject to production test.

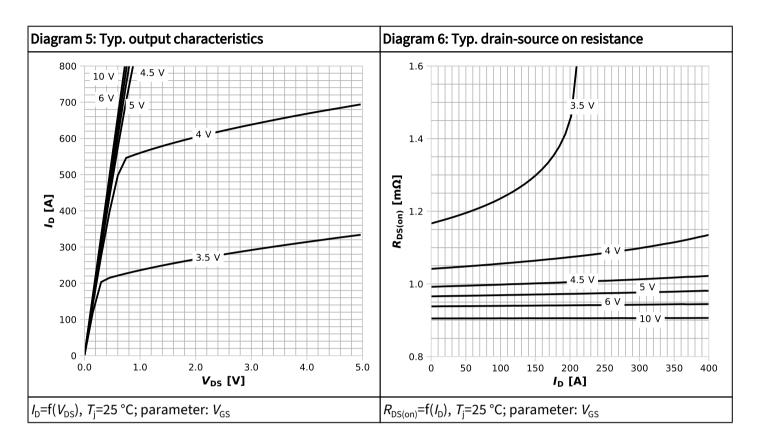


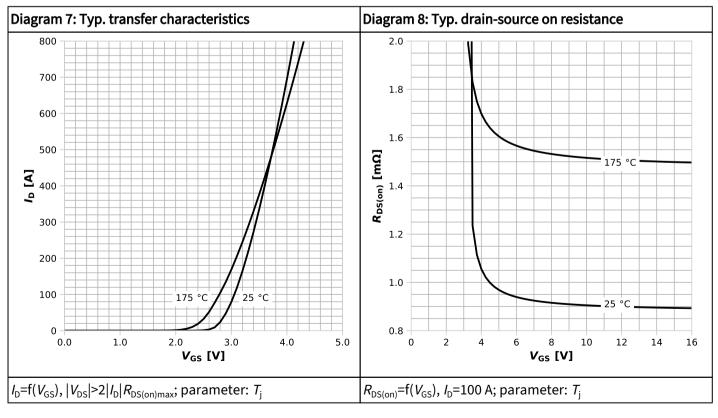
## 4 Electrical characteristics diagrams



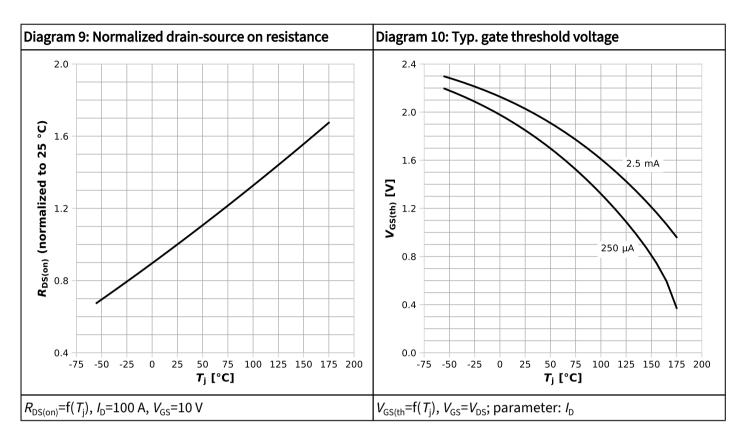


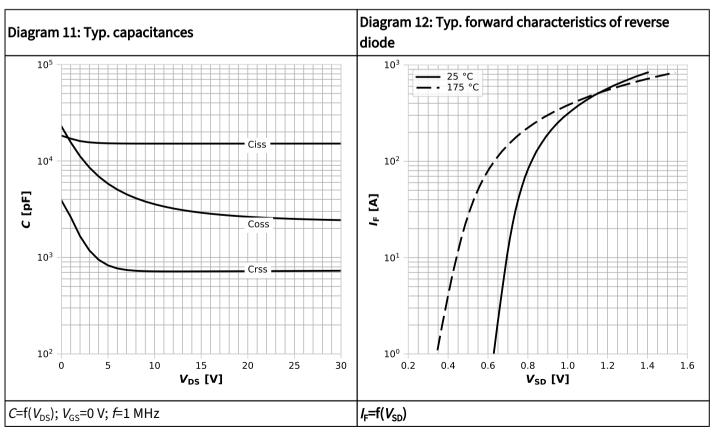




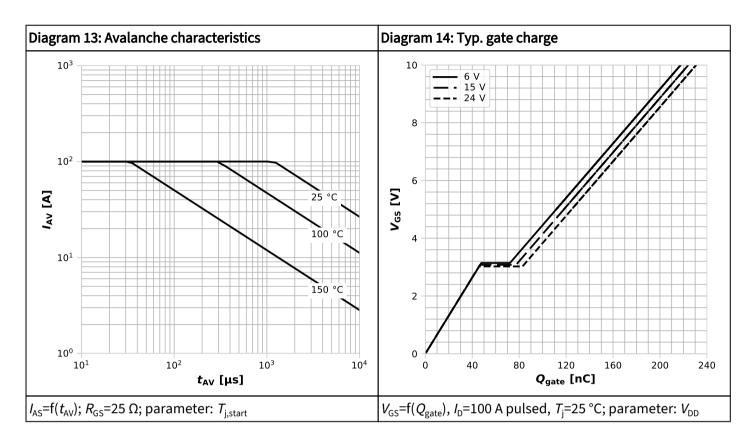


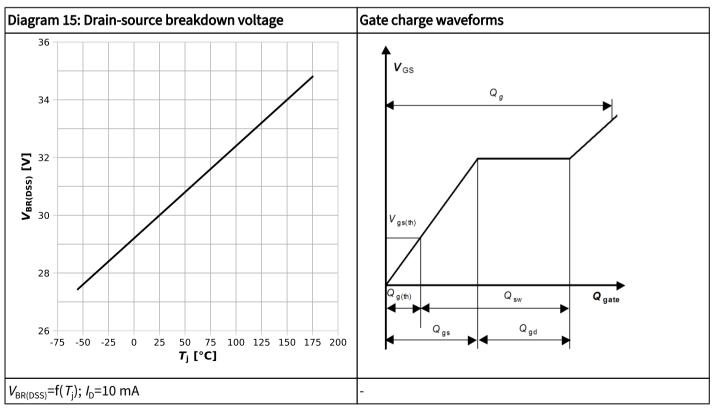














## 5 Package Outlines

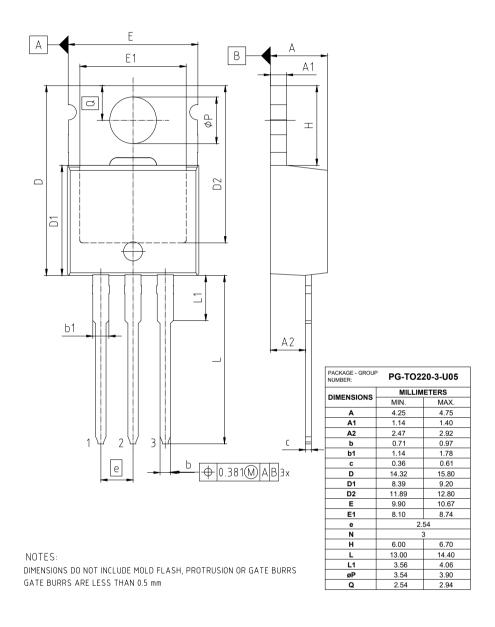


Figure 1 Outline PG-TO220-3, dimensions in mm



### **Revision History**

IPP011N03LF2S

#### Revision 2024-05-23, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2024-05-23	Release of final

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